

Notice of References Cited	Application/Control No. 10/758,913	Applicant(s)/Patent Under Reexamination ELIEZER ET AL.	
	Examiner Ramnandan Singh	Art Unit 2614	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,665,339 B1	12-2003	Adams et al.	375/238
*	D	US-5,883,930 A	03-1999	Fukushi, Mikio	375/376
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NON-PATENT DOCUMENTS

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	U	Sakuta et al, "Measurement of Phase Noise in High Performance Oscillator Using PLL-type Frequency Multiplier", Electronics and Communications in Japan, Part 2, Vol. 84, No. 8, 2001, pages 64-70.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.